

TL064x2 LOW-POWER JFET-INPUT OCTAL OPERATIONAL AMPLIFIER

SLOS134 – APRIL 1994

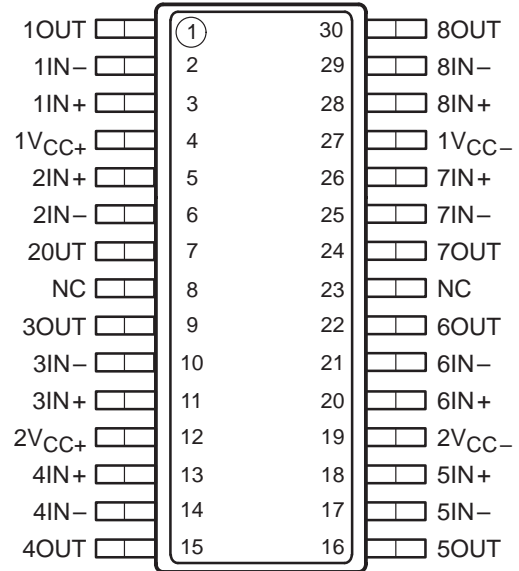
- Very Low Power Consumption
- Typical Supply Current . . . 200 μ A (Per Amplifier)
- Wide Common-Mode and Differential Voltage Ranges
- Low Input Bias and Offset Currents
- Common-Mode Input Voltage Range Includes V_{CC+}
- Output Short-Circuit Protection
- High Input Impedance . . . JFET-Input Stage
- Internal Frequency Compensation
- Latch-Up-Free Operation
- High Slew Rate . . . 3.5 V/ μ s Typ

description

The TL064x2 JFET-input operational amplifier is designed as a low-power version of the TL084x2 amplifier. It features high input impedance, wide bandwidth, high slew rate, and low input offset and bias currents. The TL064x2 features the same terminal assignments as the TL074x2 and TL084x2. Each of these JFET-input operational amplifiers incorporates well-matched, high-voltage JFET and bipolar transistors in a monolithic integrated circuit.

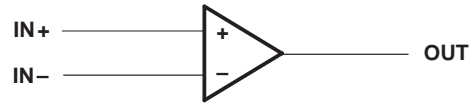
The TL064x2 is characterized for operation from 0°C to 70°C.

DB PACKAGE
(TOP VIEW)



NC – No internal connection

symbol (each amplifier)



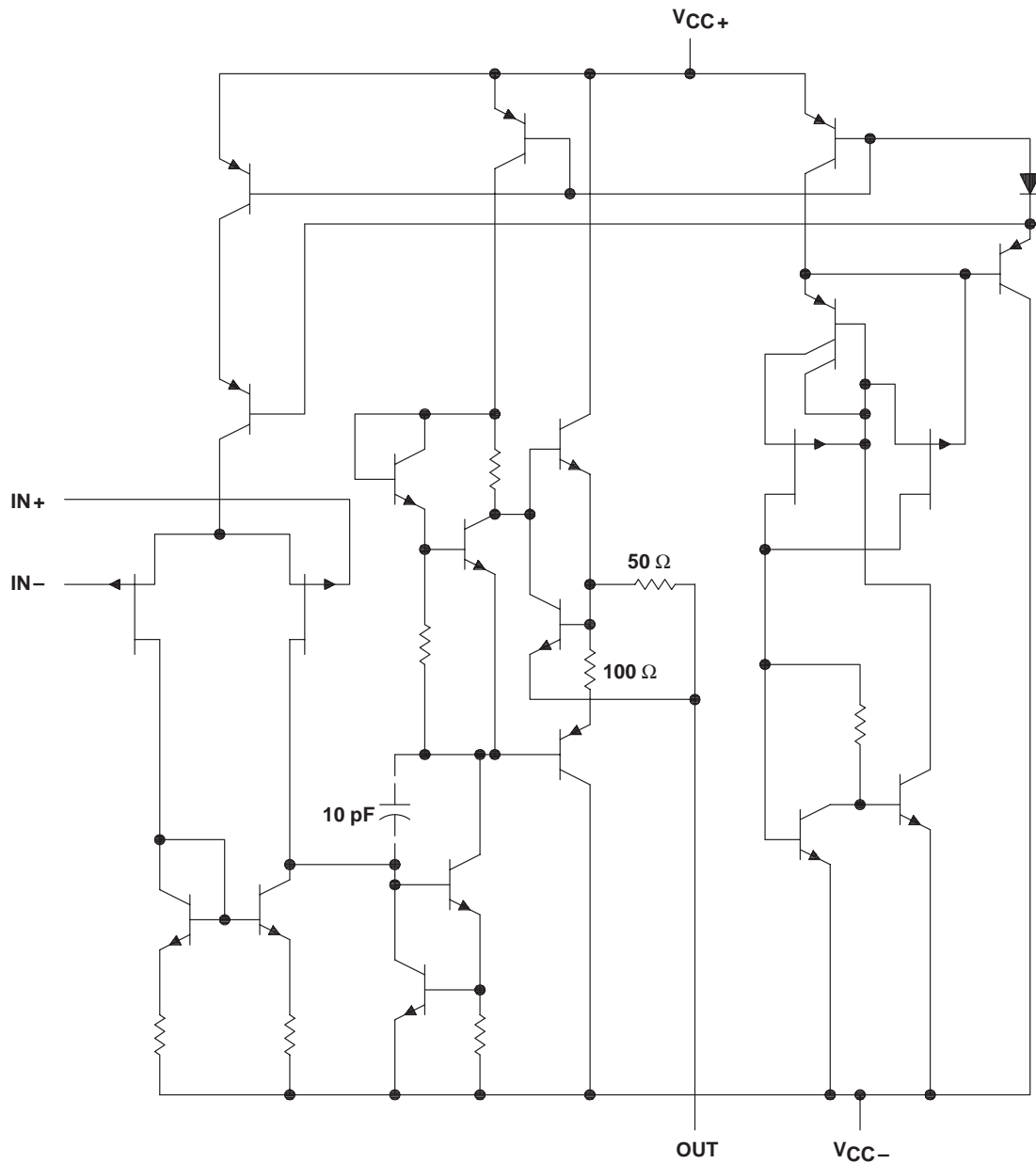
AVAILABLE OPTION

T_A	V_{IOmax} AT 25°C	PACKAGE
		SMALL OUTLINE (DB)†
0°C to 70°C	7 mV	TL064x2DBLE

† The DB package is only available left-end taped and reeled.

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schematic (each amplifier)



All component values shown are nominal.

ACTUAL DEVICE COMPONENT COUNT	
Transistors	116
Resistors	60
JFET	24
Capacitors	8
Diodes	4

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage, V_{CC+} (see Note 1)	18 V
Supply voltage, V_{CC-} (see Note 1)	–18 V
Differential input voltage, V_{ID} (see Note 2)	± 30 V
Input voltage, V_I (any input) (see Notes 1 and 3)	± 15 V
Duration of output short circuit to ground (see Note 4)	unlimited
Continuous total dissipation	See Dissipation Rating Table
Operating free-air temperature range, T_A	0°C to 70°C
Storage temperature range	-65°C to 150°C
Lead temperature 1,6 mm (1/16 inch) from case for 10 seconds	260°C

† Stresses beyond those listed under “absolute maximum ratings” may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. All voltage values, except differential voltages and V_{CC} specified for the measurement of I_{OS} , are with respect to the midpoint between V_{CC+} and V_{CC-} .
2. Differential voltages are at $IN+$ with respect to $IN-$.
3. The magnitude of the input voltage must never exceed the magnitude of the supply voltage or 15 V, whichever is less.
4. The output can be shorted to ground or to either supply. Temperature and/or supply voltages must be limited to ensure that the dissipation rating is not exceeded.

DISSIPATION RATING TABLE

PACKAGE	$T_A \leq 25^\circ\text{C}$	DERATING FACTOR	$T_A = 70^\circ\text{C}$
	POWER RATING	ABOVE $T_A = 25^\circ\text{C}$	POWER RATING
DB	1024 mW	8.2 mW/ $^\circ\text{C}$	655 mW

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electrical characteristics, $V_{CC\pm} = \pm 15\text{ V}$ (unless otherwise noted)

PARAMETER		TEST CONDITIONS†		T_A ‡	MIN	TYP	MAX	UNIT
V_{IO}	Input offset voltage	$V_O = 0,$	$R_S = 50\ \Omega$	25°C		3	15	mV
				Full range			20	
α_{VIO}	Temperature coefficient of input offset voltage	$V_O = 0,$	$R_S = 50\ \Omega$	Full range		10		$\mu\text{V}/^\circ\text{C}$
I_{IO}	Input offset current	$V_O = 0$		25°C		5	200	μA
				Full range			5	nA
I_{IB}	Input bias current§	$V_O = 0$		25°C		30	400	μA
				Full range			10	nA
V_{ICR}	Common-mode input voltage range			25°C	± 11	-12 to 15		V
V_{OM}	Maximum peak output voltage swing			25°C	± 10	± 13.5		V
				Full range	± 10			
A_{VD}	Large-signal differential voltage amplification	$V_O = \pm 10\text{ V},$	$R_L \geq 10\ \text{k}\Omega$	25°C	3	6		V/mV
				Full range	3			
B_1	Unity-gain bandwidth	$R_L = 10\ \text{k}\Omega,$		25°C		1		MHz
r_1	Input resistance			25°C		10^{12}		Ω
CMRR	Common-mode rejection ratio	$V_{IC} = V_{ICR\text{min}},$ $R_S = 50\ \Omega$	$V_O = 0,$	25°C	70	86		dB
k_{SVR}	Supply-voltage rejection ratio ($\Delta V_{CC\pm}/\Delta V_{IO}$)	$V_{CC} = \pm 9\text{ V to } \pm 15\text{ V},$ $R_S = 50\ \Omega$	$V_O = 0,$	25°C	70	95		dB
P_D	Total power dissipation (each amplifier)	$V_O = 0,$	No load	25°C		6	7.5	mW
I_{CC}	Supply current (each amplifier)	$V_O = 0,$	No load	25°C		200	250	μA
V_{O1}/V_{O2}	Crosstalk attenuation	$A_{VD} = 100$		25°C		120		dB

† All characteristics are measured under open-loop conditions with zero common-mode input voltage unless otherwise specified.

‡ Full range is 0°C to 70°C.

§ Input bias currents of a FET-input operational amplifier are normal junction reverse currents, which are temperature sensitive as shown in Figure 13. Pulse techniques must be used that maintain the junction temperature as close to the ambient temperature as possible.

operating characteristics, $V_{CC\pm} = \pm 15\text{ V}, T_A = 25^\circ\text{C}$

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
SR	Slew rate at unity gain	$V_I = 10\text{ mV},$ $C_L = 100\ \text{pF},$	$R_L = 10\ \text{k}\Omega,$ See Figure 1	1.5	3.5		V/ μs
t_r	Rise time	$V_I = 20\text{ V},$ $C_L = 100\ \text{pF},$	$R_L = 10\ \text{k}\Omega,$ See Figure 1		0.2		μs
	Overshoot factor				10%		
V_n	Equivalent input noise voltage	$R_S = 20\ \Omega,$	$f = 1\ \text{kHz}$		42		$\text{nV}/\sqrt{\text{Hz}}$



PARAMETER MEASUREMENT INFORMATION

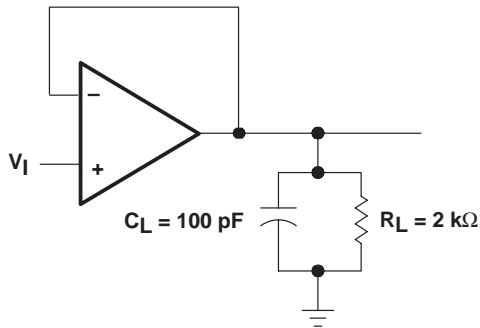


Figure 1. Unity-Gain Amplifier

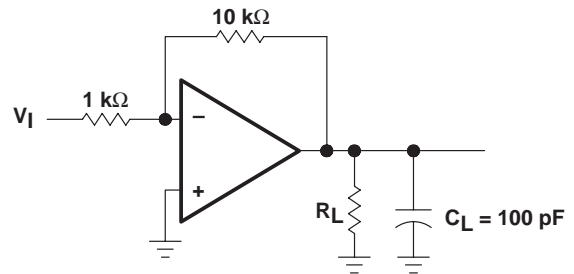


Figure 2. Gain-of-10 Inverting Amplifier

TYPICAL CHARACTERISTICS

Table of Graphs

		FIGURE	
V_{OM}	Maximum peak output voltage	vs Supply voltage	3
		vs Free-air temperature	4
		vs Load resistance	5
		vs Frequency	6
A_{VD}	Differential voltage amplification	vs Free-air temperature	7
A_{VD}	Large-signal differential voltage amplification	vs Frequency	8
I_{CC}	Supply current	vs Supply voltage	9
		vs Free-air temperature	10
P_D	Total power dissipation	vs Free-air temperature	11
		Normalized unity-gain bandwidth	12
		Normalized slew rate	12
I_{IB}	Input bias current	vs Free-air temperature	13
		Pulse response	Large signal 14
V_O	Output voltage	vs Time	15
V_n	Equivalent input noise voltage	vs Frequency	16
	Normalized phase shift	vs Free-air temperature	12

TYPICAL CHARACTERISTICS

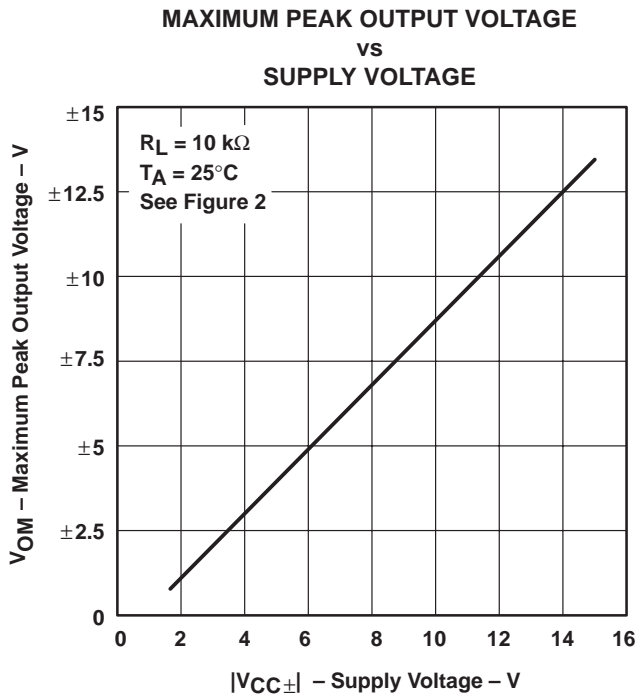


Figure 3

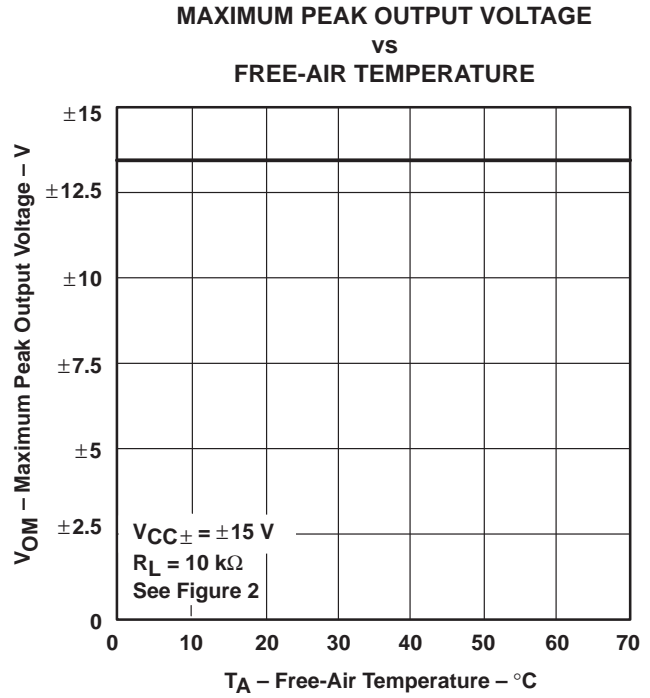


Figure 4

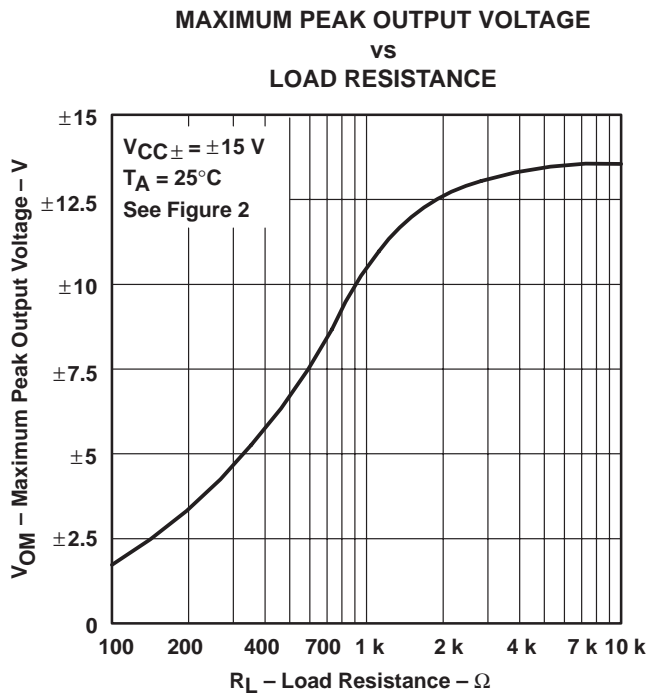


Figure 5

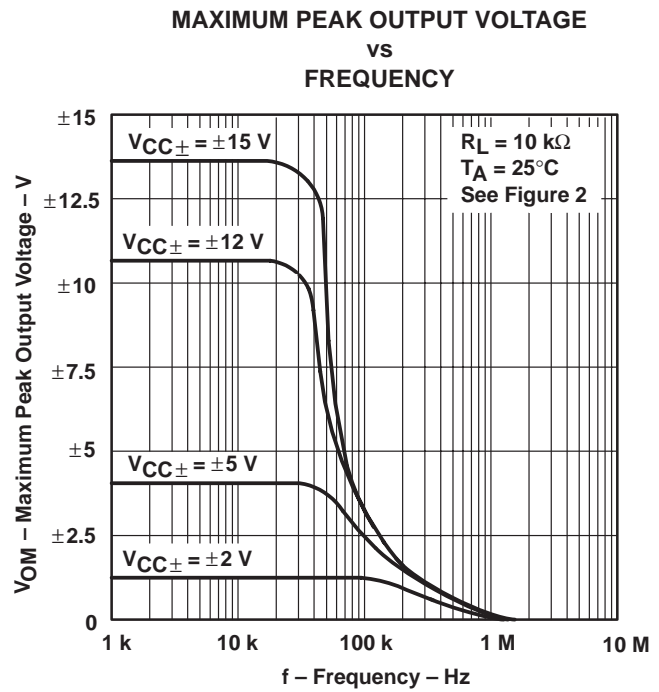


Figure 6

TYPICAL CHARACTERISTICS

DIFFERENTIAL VOLTAGE AMPLIFICATION
 vs
 FREE-AIR TEMPERATURE

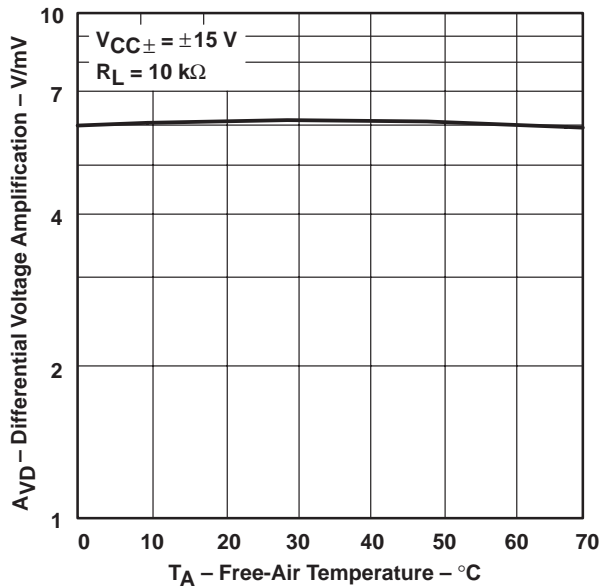


Figure 7

LARGE-SIGNAL
 DIFFERENTIAL VOLTAGE
 AMPLIFICATION AND PHASE SHIFT
 vs
 FREQUENCY

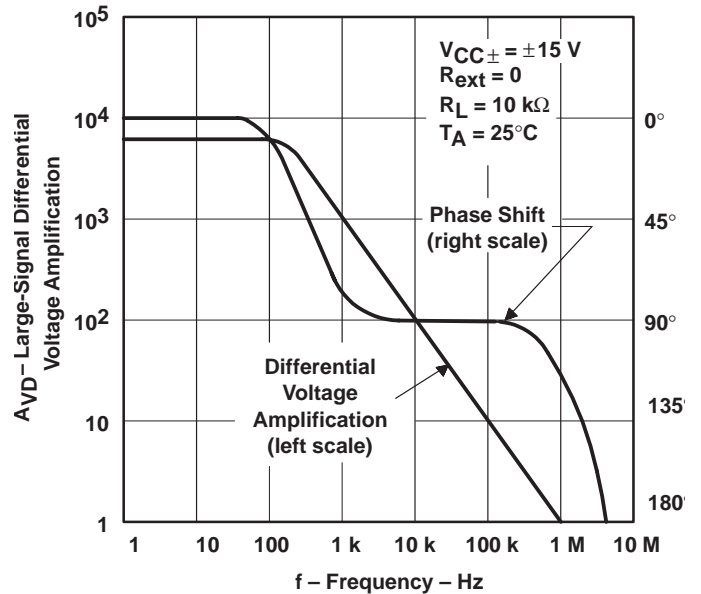


Figure 8

SUPPLY CURRENT
 vs
 SUPPLY VOLTAGE

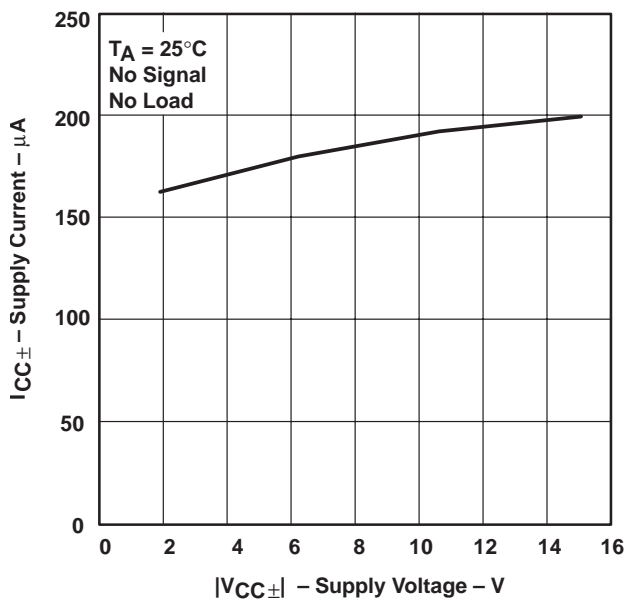


Figure 9

SUPPLY CURRENT
 vs
 FREE-AIR TEMPERATURE

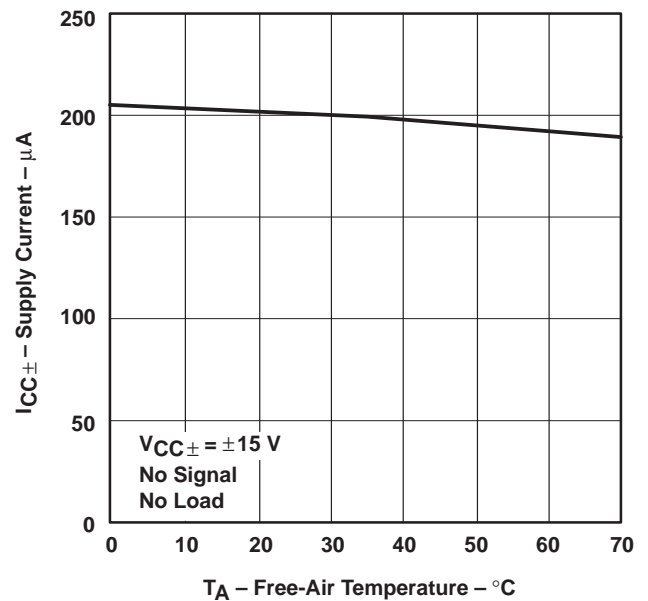


Figure 10

TYPICAL CHARACTERISTICS

TOTAL POWER DISSIPATION
 vs
 FREE-AIR TEMPERATURE

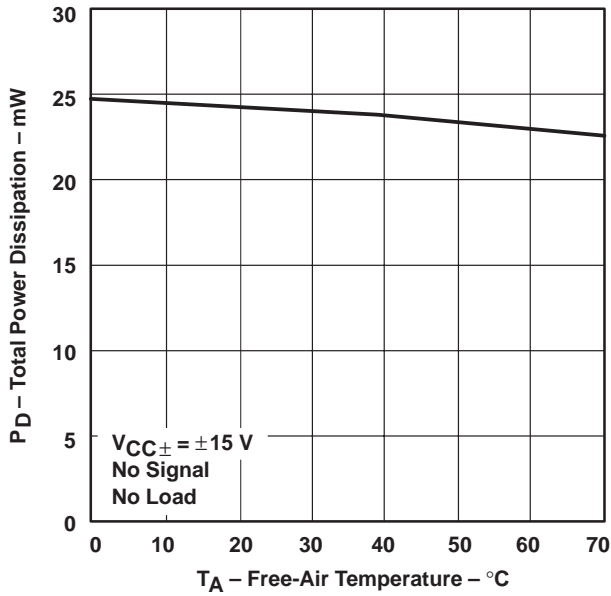


Figure 11

NORMALIZED UNITY-GAIN BANDWIDTH,
 NORMALIZED SLEW RATE, AND
 NORMALIZED PHASE SHIFT
 vs
 FREE-AIR TEMPERATURE

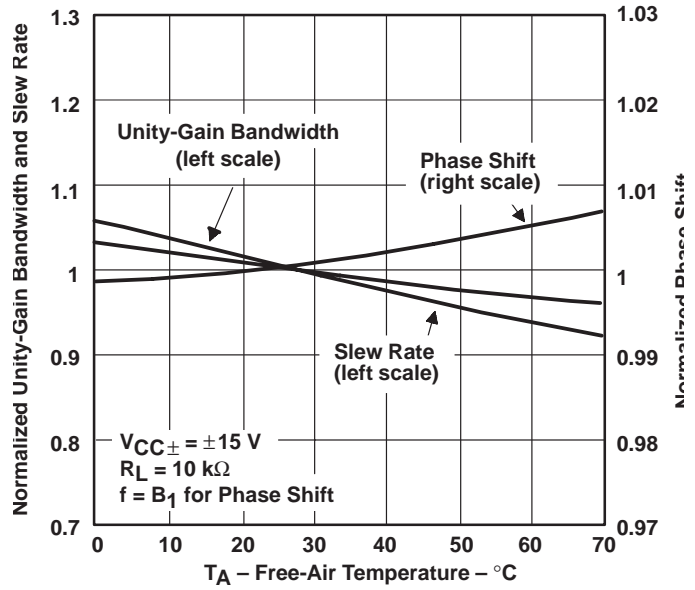


Figure 12

INPUT BIAS CURRENT
 vs
 FREE-AIR TEMPERATURE

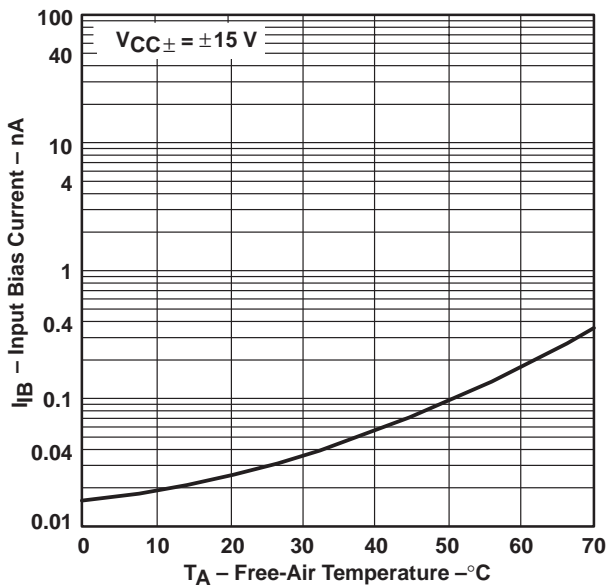


Figure 13

VOLTAGE FOLLOWER
 LARGE SIGNAL PULSE RESPONSE

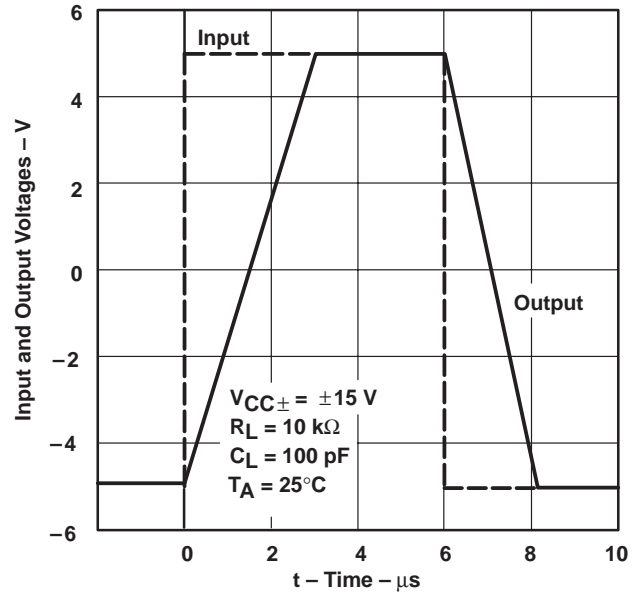


Figure 14

TYPICAL CHARACTERISTICS

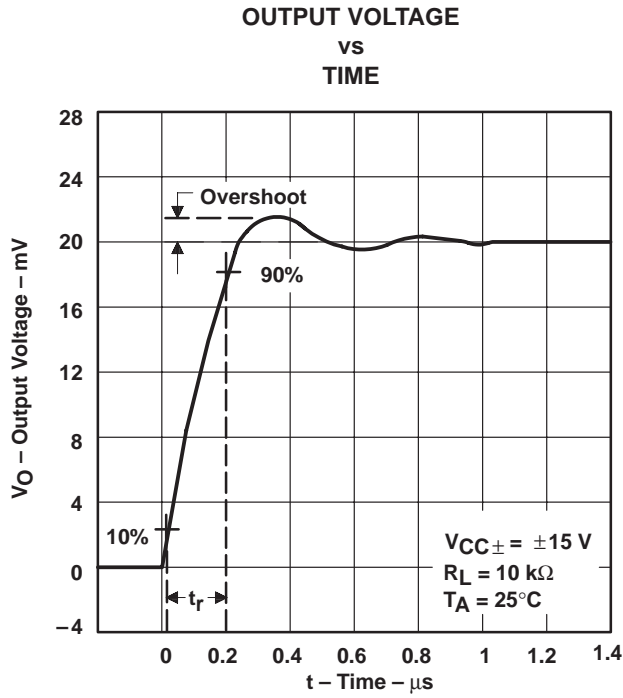


Figure 15

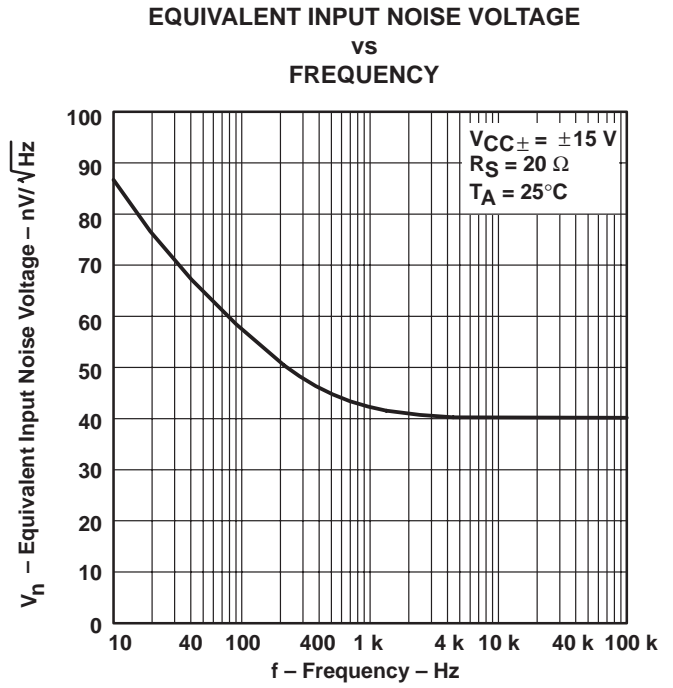


Figure 16

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